Application/Control No. Applicant(s)/Patent Under Reexamination 10/620,917 MADURAWE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ly D Pham 2818 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-6,282,124 B1 08-2001 Van Houdt et al. 365/185.28 * US-6,275,961 B1 08-2001 Roohparvar, Frankie 714/718 В 09-1999 Briner, Michael S. 365/185.3 US-5,953,256 A С Korsh et al. 365/185.24 US-5,901,089 A 05-1999 D 10-1998 Tanzawa et al. 365/229 US-5,828,621 A Ε 10-1998 Asano et al. 438/258 F US-5,824,583 A * 09-1998 Korsh et al. 365/185.24 US-5,815,439 A G * 257/316 05-1998 Mehrad, Freidoon н US-5,753,952 A * 04-1997 Kato et al. 365/185.22 US-5,625,591 A * 365/185.18 10-1996 Miyawaki et al. US-5,563,824 A * US-5,537,358 A 07-1996 Fong, Vincent L. 365/218 Κ * 02-1996 Haddad et al. 365/185.27 US-5,491,657 A L * 365/185.19 US-5,132,935 A 07-1992 Ashmore, Jr., Benjamin H. М FOREIGN PATENT DOCUMENTS Document Number Date Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р O R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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